Application/Control No.	Applicant(s)/Patent under Reexamination
10/752,388	KIM ET AL.
Examiner	Art Unit

2617

CongVan Tran

SEARCHED						
Class	Subclass	Date	Examiner			
370	252 441 332 335	8/13/2007	СТ			
455	63.1 114.2	8/13/2007	CT.			
	·278.1 296	8/13/2007	СТ			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
370	252 441	8/13/2007	СТ		
455	114.1 · . 296	8/13/2007	СТ		

SEARCH I (INCLUDING SEAR	CH S	TRATEGY	)
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